

RF Exposure Evaluation Report

Product : Wireless dynamic multi-parameter holter
Trade mark : N/A
Model/Type reference : M5,M12,Lepod,Lepod Pro,LMT-5,LMT-12
Test Model No. : M12
Serial Number : N/A
Report Number : EED32O80211002
FCC ID : 2AD XK-8100
Date of Issue : Mar. 30, 2022
: 47 CFR Part 1.1307
: 47 CFR Part 2.1093
Test Standards : KDB447498D04 Interim General RF
Exposure Guidance
Test result : PASS

Prepared for:

Shenzhen Viatom Technology Co., Ltd.
4E, Building 3, Tingwei Industrial Park, No.6 Liufang Road, Block
67,Xin'an Street, Baoan District, Shenzhen, 518101, Guangdong, China

Prepared by:

Centre Testing International Group Co., Ltd.
Hongwei Industrial Zone, Bao'an 70 District,
Shenzhen, Guangdong, China
TEL: +86-755-3368 3668
FAX: +86-755-3368 3385

Compiled by:

Frazer. Li

Reviewed by:

Avon Ma

Approved by:

David Wang

Date:

Mar. 30, 2022

David Wang

Check No.: 4753210222



1 Version

Version No.	Date	Description
00	Mar. 30, 2022	Original

2 Contents

	Page
1 VERSION.....	2
2 CONTENTS.....	3
3 GENERAL INFORMATION.....	4
3.1 CLIENT INFORMATION.....	4
3.2 GENERAL DESCRIPTION OF EUT.....	4
3.3 GENERAL DESCRIPTION OF BLE.....	4
3.4 TEST LOCATION.....	5
3.5 DEVIATION FROM STANDARDS.....	5
3.6 ABNORMALITIES FROM STANDARD CONDITIONS.....	5
3.7 OTHER INFORMATION REQUESTED BY THE CUSTOMER.....	5
4 SAR EVALUATION.....	6
4.1 RF EXPOSURE COMPLIANCE REQUIREMENT.....	6
4.1.1 Standard Requirement.....	6
4.1.2 EUT RF Exposure.....	7
PHOTOGRAPHS OF EUT CONSTRUCTIONAL DETAILS.....	8

3 General Information

3.1 Client Information

Applicant:	Shenzhen Viatom Technology Co., Ltd.
Address of Applicant:	4E, Building 3, Tingwei Industrial Park, No.6 Liufang Road, Block 67,Xin'an Street, Baoan District, Shenzhen, 518101, Guangdong, China
Manufacturer:	Shenzhen Viatom Technology Co., Ltd.
Address of Manufacturer:	4E, Building 3, Tingwei Industrial Park, No.6 Liufang Road, Block 67,Xin'an Street, Baoan District, Shenzhen, 518101, Guangdong, China
Factory:	Shenzhen Viatom Technology Co., Ltd.
Address of Factory:	4E, Building 3, Tingwei Industrial Park, No.6 Liufang Road, Block 67,Xin'an Street, Baoan District, Shenzhen, 518101, Guangdong, China

3.2 General Description of EUT

Product Name:	Wireless dynamic multi-parameter holter	
Mode No.:	M5,M12,Lepod,Lepod Pro,LMT-5,LMT-12	
Test Mode No.:	M12	
Trade mark:	N/A	
EUT Supports Radios application:	Bluetooth 5.1 dual mode: 2402-2480MHz	
Bluetooth Version:	V5.1	
Product Type:	☐ Mobile ☒ Portable ☐ Fix Location	
Power Supply:	Battery:	DC 3.8V,1.52Wh,400mAh
Test Voltage:	DC 3.8V	
Sample Received Date:	Mar . 22, 2022	
Sample tested Date:	Mar . 28, 2022 to Mar. 29, 2022	
Remark:	Company Name and Address shown on Report, the sample(s) and sample Information was/ were provided by the applicant who should be responsible for the authenticity which CTI hasn't verified. Model No.: M5,M12,Lepod,Lepod Pro,LMT-5,LMT-12 Only the model M12 was tested, since the electrical circuit design, layout, components used and internal wiring were identical for the above models, with difference being shell color and whether or not a core conductance cable is available.	

3.3 General Description of BLE

Operation Frequency:	2402MHz~2480MHz
Modulation Type:	GFSK
Transfer Rate:	☒ 1Mbps ☒ 2Mbps
Number of Channel:	40
Antenna Type:	Internal Antenna
Antenna Gain:	3.45 dBi

3.4 Test Location

All tests were performed at:

Centre Testing International Group Co., Ltd

Building C, Hongwei Industrial Park Block 70, Bao'an District, Shenzhen, China

Telephone: +86 (0) 755 33683668 Fax: +86 (0) 755 33683385

No tests were sub-contracted.

FCC Designation No.: CN1164

3.5 Deviation from Standards

None.

3.6 Abnormalities from Standard Conditions

None.

3.7 Other Information Requested by the Customer

None.

4 SAR Evaluation

4.1 RF Exposure Compliance Requirement

4.1.1 Standard Requirement

According to KDB447498D04 Interim General RF Exposure Guidance
Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Exclusion Threshold condition, listed below, is satisfied.

Limits

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$$\left[\frac{(\text{max. power of channel, including tune-up tolerance, mW})}{(\text{min. test separation distance, mm})} \right] \cdot \sqrt{f(\text{GHz})} \leq 3.0 \text{ for 1-g SAR and } \leq 7.5 \text{ for 10-g extremity SAR, where}$$

$f(\text{GHz})$ is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation¹⁷

The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion

4.1.2 EUT RF Exposure

1) For BLE 1Mbps

Measurement Data

GFSK mode 1Mbps				
Test channel	Peak Output Power (dBm)	Tune up tolerance (dBm)	Maximum tune-up Power	
			(dBm)	(mW)
Lowest(2402MHz)	-0.31	-1.0±1	0	1.000
Middle(2440MHz)	-0.19	-1.0±1	0	1.000
Highest(2480MHz)	-0.55	-1.0±1	0	1.000

2) For BLE 2Mbps

Measurement Data

GFSK mode 2Mbps				
Test channel	Peak Output Power (dBm)	Tune up tolerance (dBm)	Maximum tune-up Power	
			(dBm)	(mW)
Lowest(2402MHz)	-0.38	-1.0±1	0	1.000
Middle(2440MHz)	-0.25	-1.0±1	0	1.000
Highest(2480MHz)	-0.60	-1.0±1	0	1.000

Worst case: GFSK mode 1Mbps

Channel	Maximum Peak Conducted Output Power (dBm)	Tune up tolerance (dBm)	Maximum tune- up Power		Calculated value	Exclusion threshold
			(dBm)	(mW)		
Lowest (2402MHz)	-0.31	-1.0±1	0	1.000	0.310	3.0
Middle (2440MHz)	-0.19	-1.0±1	0	1.000	0.312	
Highest (2480MHz)	-0.55	-1.0±1	0	1.000	0.315	

Conclusion: the calculated value ≤3.0, SAR is exempted.

Remark: The Max Conducted Peak Output Power data refer to report Report No.: EED32O80211001.

PHOTOGRAPHS OF EUT Constructional Details

Refer to Report No. EED32O80211001 for EUT external and internal photos.

The test report is effective only with both signature and specialized stamp, The result(s) shown in this report refer only to the sample(s) tested. Without written approval of CTI, this report can't be reproduced except in full.

*** End of Report ***